Special Issue

Silicon Nanowires and Their Applications

Message from the Guest Editors

We invite you to contribute to a Special Issue of the journal *Applied Sciences*, "Silicon Nanowires and Their Applications", which aims to present recent advances in the investigation silicon nanowires (SiNWs) and SiNW-based devices including also fabrication strategies, SiNW characterization, and theoretical studies. SiNWs provide a unique set of material and morphological properties comprising 1D transport phenomena and a high surface to volume ratio that enable a broad spectrum of applications. The enhanced electrostatics in SiNW devices offers for instance the possibility to scale field effect transistors (FETs) down to

Guest Editors

Prof. Dr. Qing-Tai Zhao

Peter Grünberg Institute 9, Forschungszentrum Jülich, 52425 Jülich, Germany

Prof. Dr. Steffen Strehle

Microsystems Technology, Technische Universität Ilmenau, Germany (Image: © E. Eberhardt, Ulm University)

Deadline for manuscript submissions

closed (30 June 2019)



Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5 CiteScore 5.5



mdpi.com/si/11141

Applied Sciences Editorial Office MDPI, Grosspeteranlage 5 4052 Basel, Switzerland Tel: +41 61 683 77 34 applsci@mdpi.com

mdpi.com/journal/applsci





Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5 CiteScore 5.5



About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

